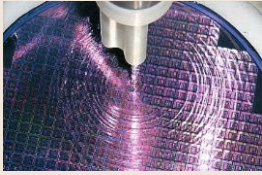


# Xper-IP Mini

Powerful and affordable non-destructive thickness measuring system  
by NANOBASE



## For what applications do we need **Xper-IP Mini**?



### Semiconductor

- Wafer
- Si for PV panel



### Flat Panel Display

- TFT-LCD, AM-OLED
- Diamond-like carbon
- High-functional film



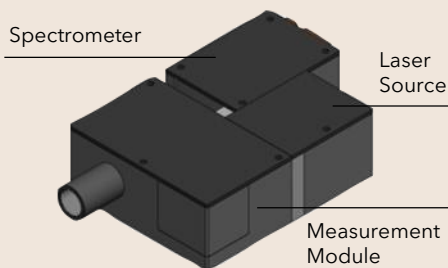
### Films and Polymers

- Optical film
- Medical polymer materials

## Why do our customers choose **Xper-IP Mini**?

- Absolute thickness measurement with accuracy of  $\pm 0.2\%$  in full range
- Exceptional long-term measurement repeatability of  $\pm 0.003\%$  in full range
- Broad measurement range of 1.2 mm to 0.03 mm
- Intuitive software with both-surface analysis capacity
- Simultaneous multiple layer measuring capability
- Rugged and compact design suitable for laboratory and manufacturing environments

## Xper-IP Mini Specifications



### Product Size

144.5 x 90 x 37 (mm)

### Thickness Measurement Sensor Head

- Resolution (Z): 10 nm
- Accuracy (Z):  $\pm 0.2\%$  of full scale
- Standoff distance: up to 150 mm from objective
- Measurement range (Z): 0.03 ~ 1.2 mm
- Measurement speed: 100 Hz

### Laser Source

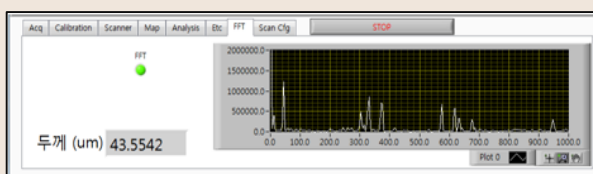
840 nm SLD

### Surface Profile Measurement Sensor Head Options

- One shot measurement range (X): 0.5 ~ 2 mm
- One shot measurement data count: 100 points
- Resolution (X): 5 ~ 20  $\mu\text{m}$  depending on an objective lens
- Resolution (Z): 15 nm
- Accuracy (Z):  $\pm 0.2\%$  of full scale
- Measurement range (Z): 1.8 mm
- Measurement speed: 30 Hz

## Xper-IP Mini Measurement Data

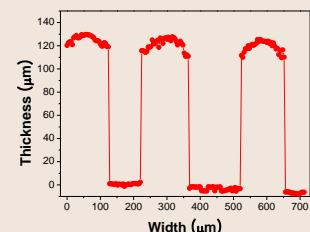
### Interferometric Thickness Measurement



### Interferometric Surface Measurement



Microscopic image



Surface information